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ELECTRICAL TEST PROBE WEDGE TIP

Inventor: Julie A. Campbell, Beaverton, OR

(US)

Assignee: LeCroy Corporation, Beaverton, OR (73)

(US)

14 Years Term:

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(51)

U.S. Cl. D10/80 (52)

(58)324/761, 758, 756, 755, 158 P; 439/482

References Cited (56)

U.S. PATENT DOCUMENTS

D. 427,091	*	6/2000	Suurmeijer	 D10/80
D. 427,535	*	7/2000	Suurmeijer	 D10/80

^{*} cited by examiner

Primary Examiner—Antoine Duval Davis (74) Attorney, Agent, or Firm—Miller Nash LLP

CLAIM (57)

The ornamental design for an electrical test probe wedge tip, as shown and described.

DESCRIPTION

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FIG. 1 is a general perspective view of an electrical test probe wedge tip showing the new design, wherein the broken line depiction of the shaft is included merely for illustrative purposes and forms no part of the claimed design.

FIG. 2 is a front view of the electrical test probe wedge tip, wherein the broken line depiction of the shaft is included merely for illustrative purposes and forms no part of the claimed design.

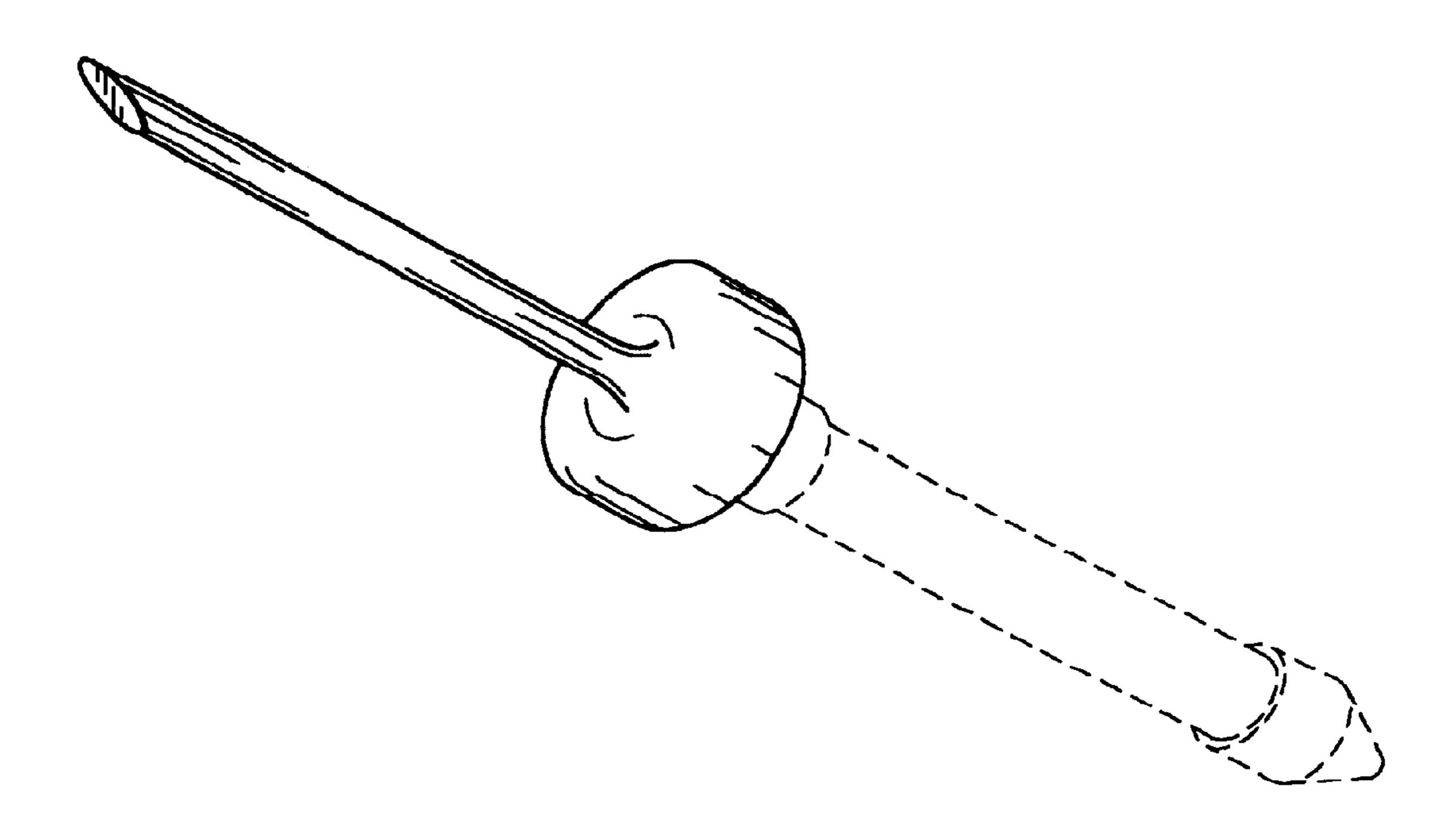
FIG. 3 is a right side view of the electrical test probe wedge tip, the left side view being a mirror image thereof, wherein the broken line depiction of the shaft is included merely for illustrative purposes and forms no part of the claimed design.

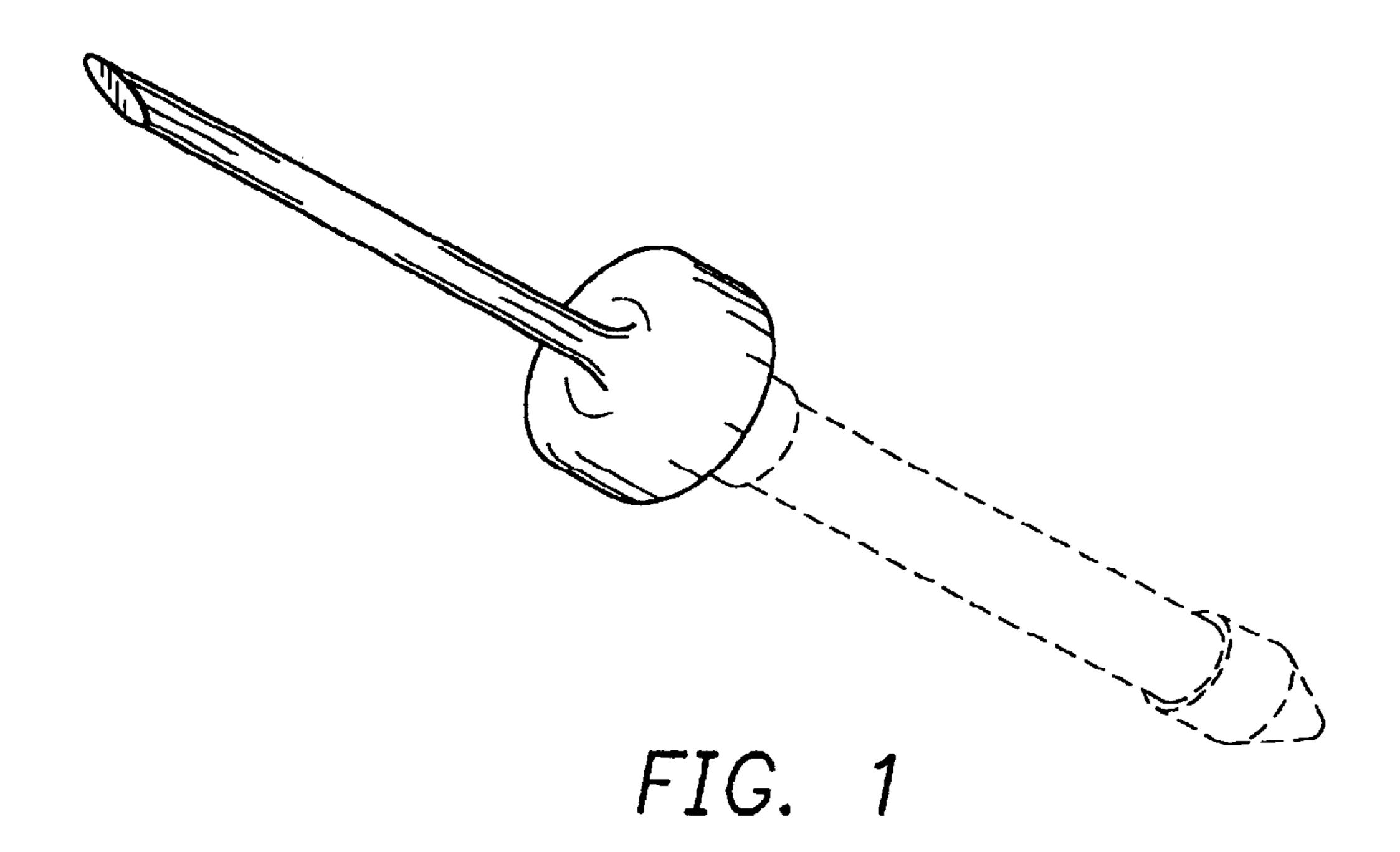
FIG. 4 is a back view of the electrical test probe wedge tip, wherein the broken line depiction of the shaft is included merely for illustrative purposes and forms no part of the claimed design.

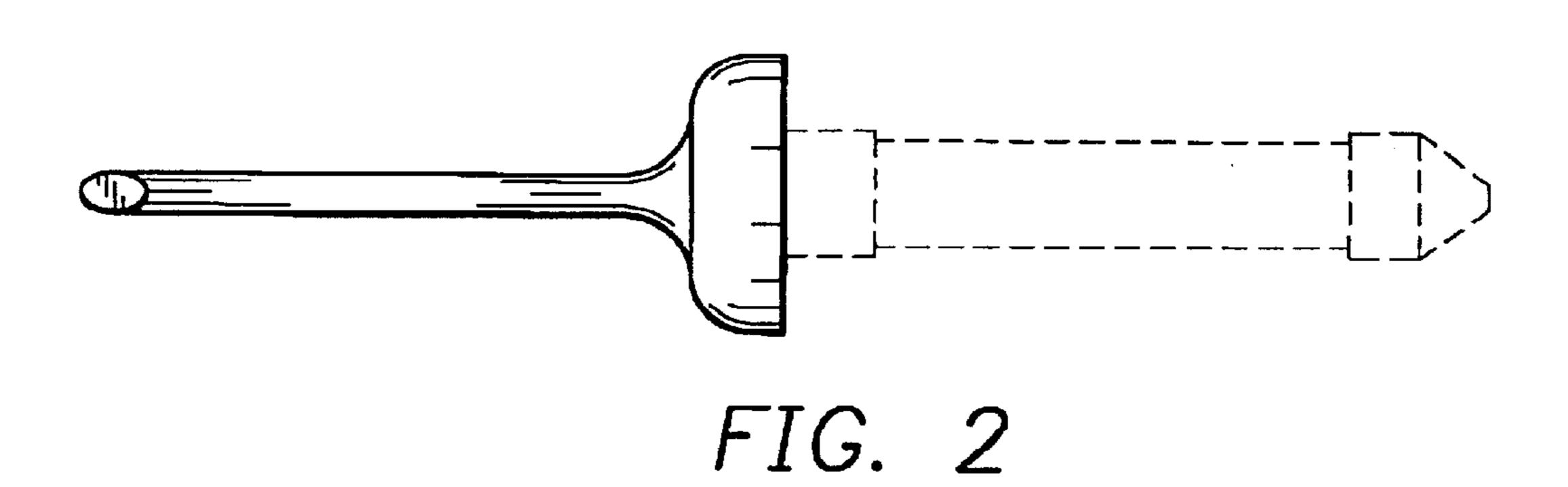
FIG. 5 is a top view of the electrical test probe wedge tip; and,

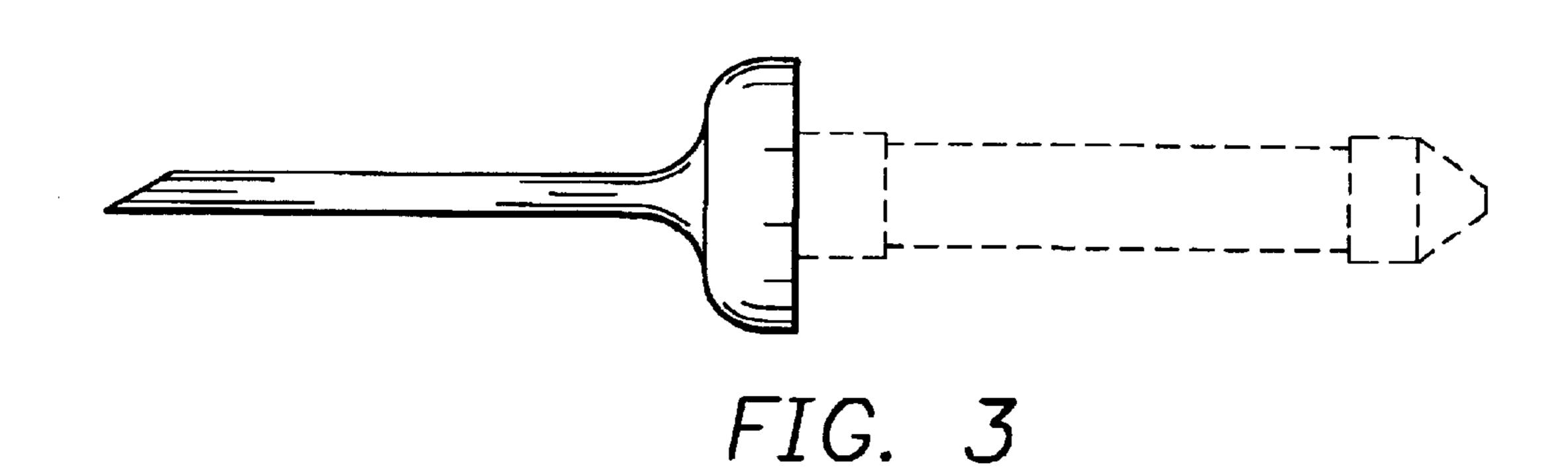
FIG. 6 is a bottom view of the electrical test probe wedge tip.

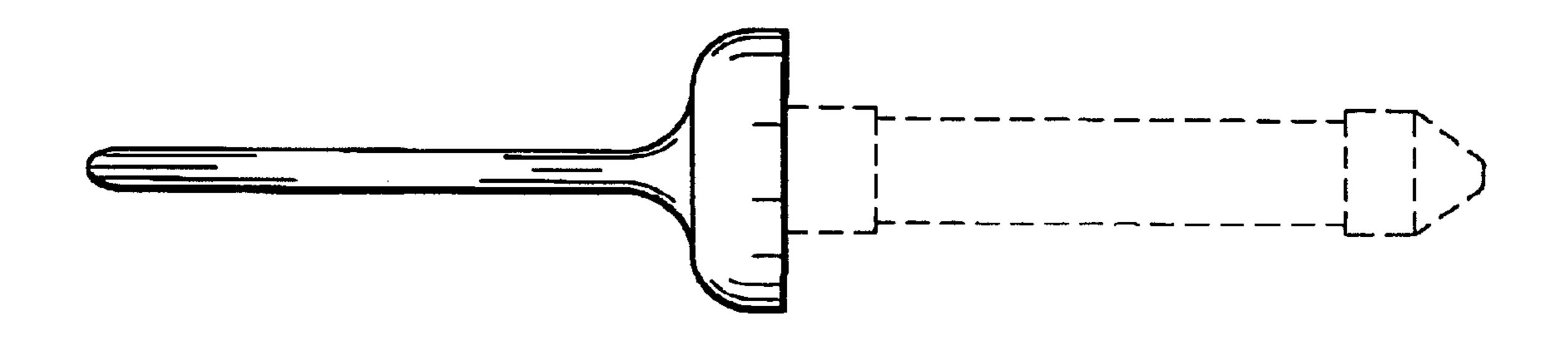
1 Claim, 2 Drawing Sheets











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FIG. 4

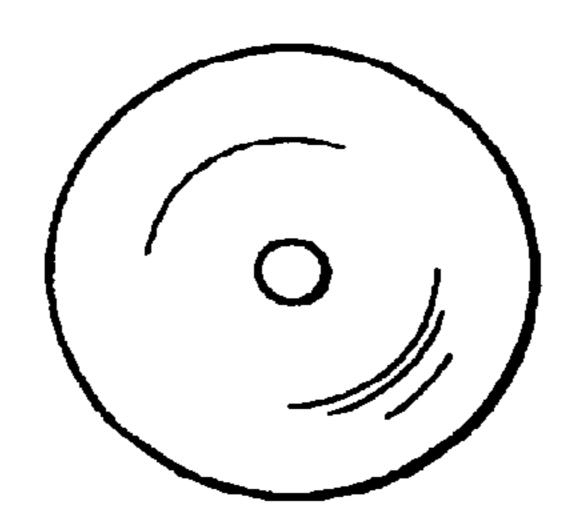


FIG. 5

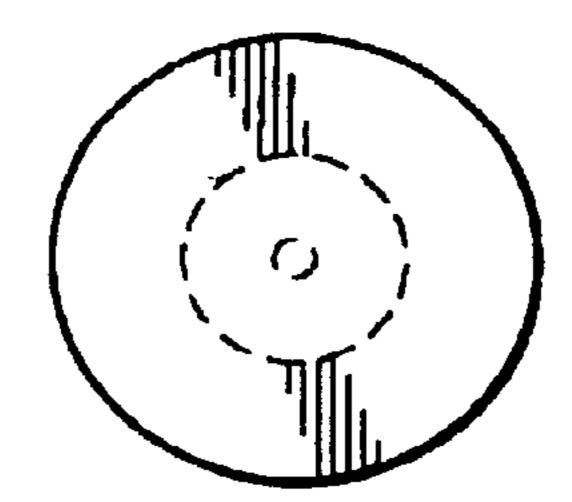


FIG. 6